

Application/Control No.	Applicant(s)/Patent under Reexamination
10/031,399	SATOH, KATSUHISA
Examiner	Art Unit
Tianjie Chen	2652

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Class	Subclass	Date	Examiner
Updated		9/19/2005	TJ
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INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
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